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Optimizing CMOS Circuits for Low Power using Transistor Reordering - Eur opean Design and Test Conference, 1996. ED&TC 96. Proceedings Author: IEEE Created Date: http://cs.upc.edu/~jordicf/Research/gavina/BIB/files/edtc96_lowpower.pdf

1997, European Design and Test Conference, Ed&Tc (European Test Conference//Proceedings) [European Design and Test Conference] on Amazon.com. *FREE* shipping on <http://www.amazon.com/1997-European-Design-Conference-Proceedings/dp/0818677864>

Simple mixed-signal circuits can be In Proceedings European Design & Test Conference (ED&TC Proceedings European Design & Test Conference (ED&TC), IEEE <http://www.sciencedirect.com/science/article/pii/S1571066106003434>

OSCILLATION-BASED TESTING METHOD FOR Proc. of the European Design and Test Conference (ED&TC Based Test of Integrated Filters", IEEE Design <http://casopisi.junis.ni.ac.rs/index.php/FUElectEnerg/article/view/256/523>

European Design and Test Conference, 1994. EDAC, The European Conference on Design Automation. European Design and Test Conference, 1996. ED&TC 96. <http://ieeexplore.ieee.org/xpl/mostRecentIssue.jsp?punumber=946>

A BDD-based Frontend for Retargetable European Design & Test Conference (ED & TC: - In Proceedings of the IEEE / ACM International Conference on VLSI <http://citeseerx.ist.psu.edu/showciting?doi=10.1.1.50.1520>

a specification-level intermediate format for system design - European Design and Test Conference, 1995. ED&TC 1995, Proceedings. Author: IEEE
http://www.cs.ucr.edu/~vahid/pubs/edtc95_slif.pdf

European Design & Test Conference (EDAC-ETC Euro-DAC, 1996 . R P. Marwedel, C. Lopez-Barrio (ed.): Special issue on ED&TC, IEEE Design & Test,
<http://hartenstein.de/MarwedelPublications.doc>

Design for testability of gated-clock FSMs - European Design and Test Conference, 1996. ED&TC 96. Proceedings Author: IEEE Created Date: 2/8/1998 6:21:46 AM
<http://icwww.epfl.ch/~demichel/publications/archive/1996/DATEconf96pg589.pdf>

(used for all products subject to European safety The new method is a reference test method Current toy safety standards focus on design principles
http://en.wikipedia.org/wiki/Toy_safety

Procedure Cloning: A Transformation For Improved System-level Functional Partitioning - European Design and Test Conference, 1997. ED&TC 97. Proceedings Author:
http://www.cs.ucr.edu/~vahid/pubs/edtc97_clone.pdf

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IEEE Xplore. Delivering full text Proceedings of European Design and Test Conference Full Text European Design and Test Conference, 1996. ED&TC 96.
http://ieeexplore.ieee.org/xpls/abs_all.jsp?arnumber=494114

Google Scholar. Citation indices All Since 2010; IEEE Design & Test of computers, 44-53, 2000. 250: IEEE Transactions , 1996. 143:
<http://scholar.google.com/citations?user=UKPu8AMAAAJ&hl=en>

The European Design & Test Conference 1996 ED&TC Sponsored by European Design and Automation Association IEEE Computer Society/ and ACM/SIGDA European
<http://www.cecs.uci.edu/%7Epapers/compendium94-03/papers/1996/edt96/pdffiles/edtcvr.pdf>

Topics related to Compaction; IEEE DATE is the complete event for the European electronic and test A. European Design and Test Conference, 1997. ED&TC
<http://technav.ieee.org/tag/5208/>

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<https://www.linkedin.com/in/oliviercoudert>

Prof. Peter M. Maurer's Biography. Testing for VLSI Circuits," IEEE Design & Test of on the World Wide Web, European Workshop on VLSI Education,
<http://cs.ecs.baylor.edu/~maurer/maurerbi.php>

Prof. Antonis Paschalis is full Proc. of the IEEE International Test Conference 1996 Proc. of the European Design & Test Conference 1997 (ED&TC
<http://cgi.di.uoa.gr/~paschali/>

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http://ieeexplore.ieee.org/xpls/abs_all.jsp?arnumber=494114

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https://eric.ed.gov/?q=%22%22&ff1=dySince_1996&ff2=pubReports+-+Research&ff3=subSurveys&ff4=subInterviews&ff5=souGerontologist

Fast Power Loss Calculation For Digital Static Cmos Circuits - European Design and Test Conference, 1997. ED&TC 97. Proceedings Author: IEEE Created Date:
<http://blaauw.eecs.umich.edu/getFile.php?id=122&sid=vomuvflatyhha>

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"Sensitivity Analysis of Critical Parameters in Board Test," IEEE Design & Test Education Conference 1996 IEEE Asia-Pacific Conference
<http://www.engr.colostate.edu/faculty-staff/far-publications.cfm?id=7>